


<b>Search Notes</b>  	<b>Application/Control No.</b>  10057066	<b>Applicant(s)/Patent Under Reexamination</b>  XIAO, SIHAI
	<b>Examiner</b>  Pich, Ponnoreay	<b>Art Unit</b>  2135

SEARCHED			
Class	Subclass	Date	Examiner
			PP

SEARCH NOTES		
Search Notes	Date	Examiner
713/155-158 (limited by text) and text search on EAST, see notes	5/2/2007	PP

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner